Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/521,622	HAGIO ET AL.	
Examiner	Art Unit	
Susan E. Fernandez	1651	

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SEARCHED						
Class	Subclass	Date	Examiner			
435	468,470, 173.1, 173.6,410	9/28/2007	SEF			
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
·	DATE	EXMR		
EAST: US-PGPUB, USPAT, EPO, JPO, DERWENTsee search history	9/28/2007	SEF		
STN: CAPLUS, BIOSISsee search history	9/28/2007	SEF		
inventor name search: PALM and STN	9/28/2007	SEF		
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